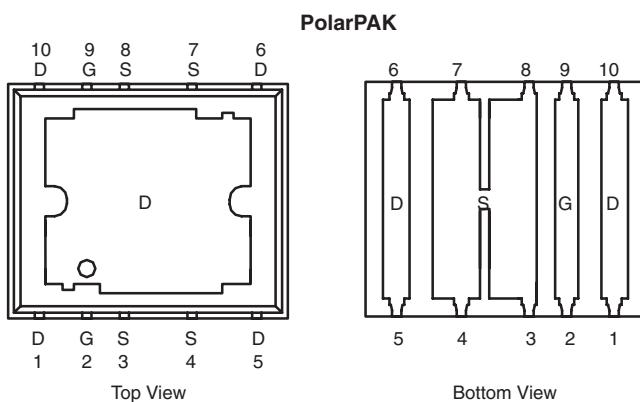


N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY				
V_{DS} (V)	$r_{DS(on)}$ (Ω)	I_D (A) ^a		
		Silicon Limit	Package Limit	Q_g (Typ)
20	0.0035 at $V_{GS} = 4.5$ V	136	50	43 nC
	0.0064 at $V_{GS} = 2.5$ V	100	50	

[Package Drawing](#)
<http://www.vishay.com/doc?73398>


Top surface is connected to pins 1, 5, 6, and 10

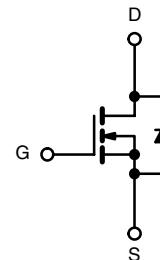
Ordering Information: SiE820DF-T1-E3 (Lead (Pb)-free)

FEATURES

- Extremely Low Q_{gd} WFET Technology for Low Switching Losses
- TrenchFET® Power MOSFET
- Ultra Low Thermal Resistance Using Top-Exposed PolarPAK® Package for Double-Sided Cooling
- Leadframe-Based New Encapsulated Package
 - Die Not Exposed
 - Same Layout Regardless of Die Size
- Low Q_{gd}/Q_{gs} Ratio Helps Prevent Shoot-Through
- 100 % R_g and UIS Tested


APPLICATIONS

- VRM
- DC/DC Conversion
- Synchronous Rectification



N-Channel MOSFET

[For Related Documents](#)
<http://www.vishay.com/ppg?74447>

ABSOLUTE MAXIMUM RATINGS $T_A = 25$ °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 12	
Continuous Drain Current ($T_J = 150$ °C)	I_D	136 (Silicon Limit)	A
		50 ^a (Package Limit)	
		50 ^a	
		30 ^{b, c}	
Pulsed Drain Current	I_{DM}	24 ^{b, c}	
		80	
Continuous Source-Drain Diode Current	I_S	50 ^a	
		4.3 ^{b, c}	
Single Pulse Avalanche Current	I_{AS}	30	
Avalanche Energy	E_{AS}	45	mJ
Maximum Power Dissipation	P_D	104	W
		66	
		5.2 ^{b, c}	
		3.3 ^{b, c}	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 50 to 150	
Soldering Recommendations (Peak Temperature) ^{d, e}		260	°C

Notes:

a. Package limited is 50 A.

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 sec.

d. See Solder Profile (<http://www.vishay.com/doc?73257>). The PolarPAK is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, b}	Steady State	R _{thJA}	20	24	°C/W
Maximum Junction-to-Case (Drain Top) ^a		R _{thJC} (Drain)	1	1.2	
Maximum Junction-to-Case (Source) ^{a, c}		R _{thJC} (Source)	2.8	3.4	

Notes:

- a. Surface Mounted on 1" x 1" FR4 board.
- b. Maximum under Steady State conditions is 68 °C/W.
- c. Measured at source pin (on the side of the package).

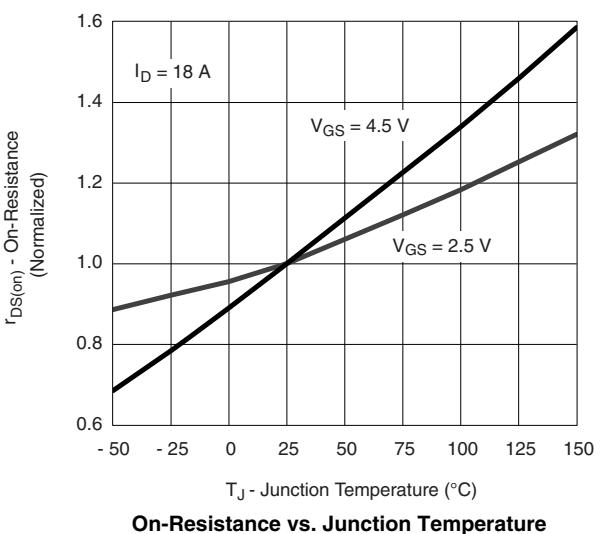
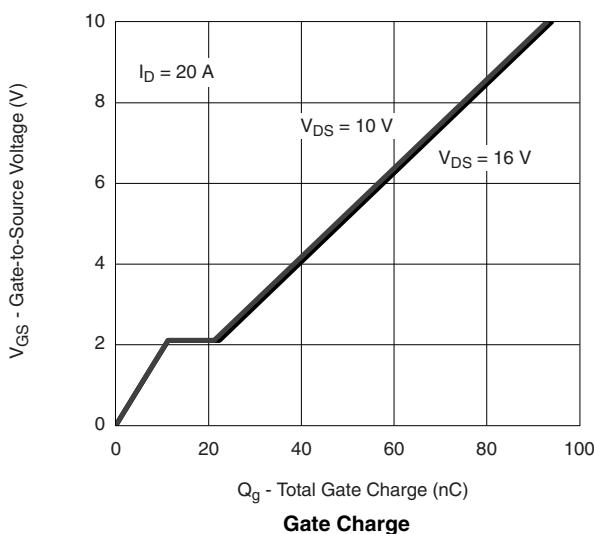
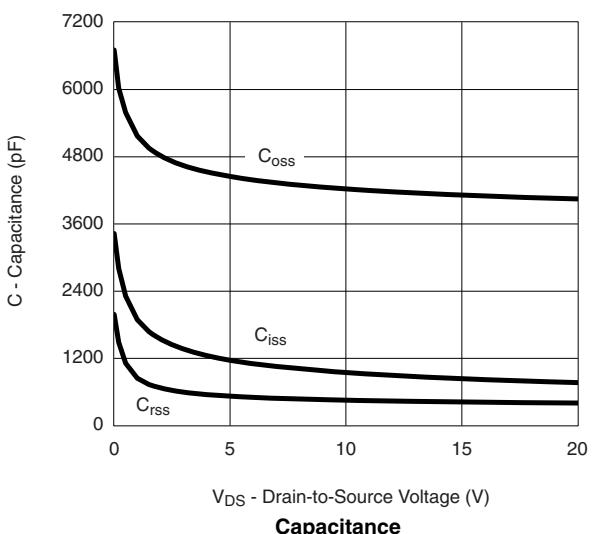
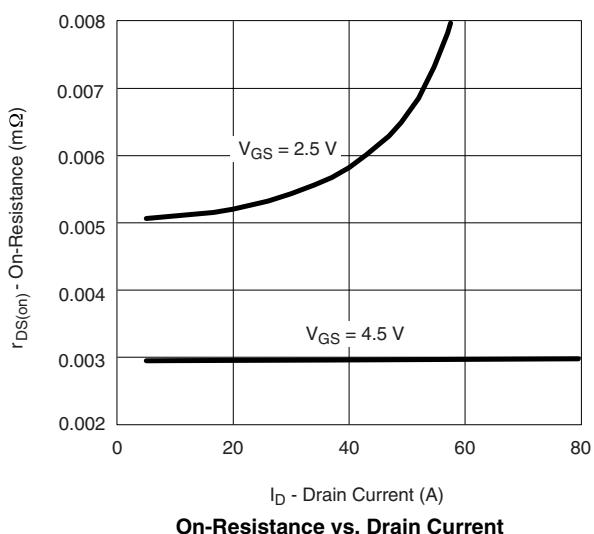
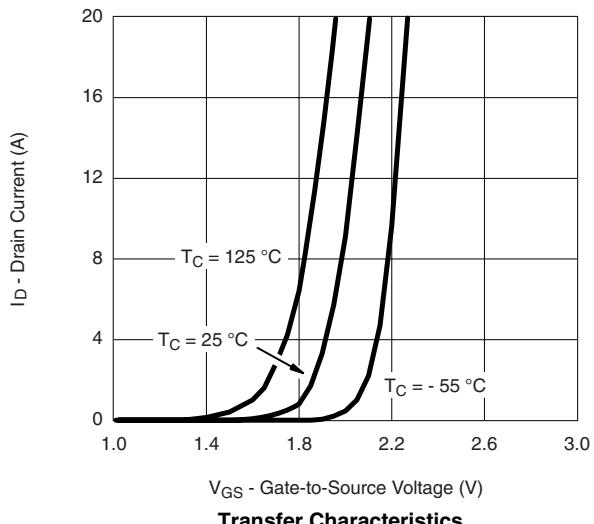
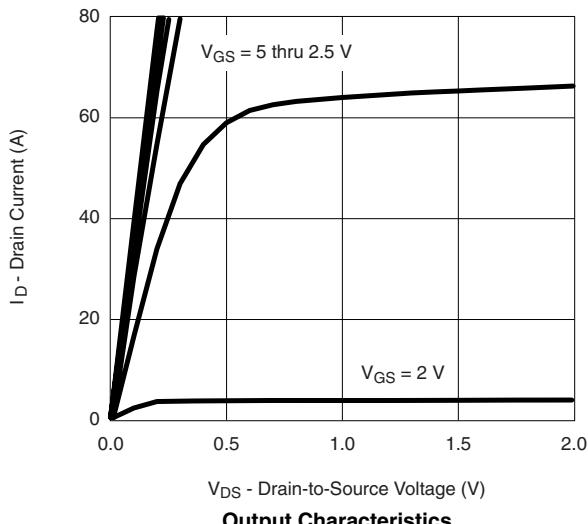
SPECIFICATIONS T_J = 25 °C, unless otherwise noted

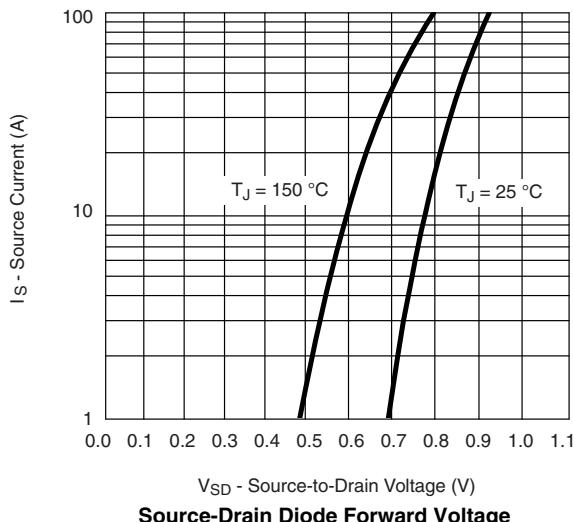
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	20			V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA		20		mV/°C
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J			- 4.8		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	0.6	1.4	2	V
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 12 V			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V			1	μA
		V _{DS} = 20 V, V _{GS} = 0 V, T _J = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≥ 5 V, V _{GS} = 4.5 V	25			A
Drain-Source On-State Resistance ^a	r _{DS(on)}	V _{GS} = 4.5 V, I _D = 18 A		0.0029	0.0035	Ω
		V _{GS} = 2.5 V, I _D = 13.4 A		0.0053	0.0064	
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 18 A		106		S
Dynamic^b						
Input Capacitance	C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		4300		pF
Output Capacitance	C _{oss}			950		
Reverse Transfer Capacitance	C _{rss}			450		
Total Gate Charge	Q _g	V _{DS} = 10 V, V _{GS} = 10 V, I _D = 20 A		95	143	nC
Gate-Source Charge	Q _{gs}	V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 20 A		43	65	
Gate-Drain Charge	Q _{gd}			11.5		
Gate Resistance	R _g			10		
Turn-on Delay Time	t _{d(on)}	f = 1 MHz V _{DD} = 10 V, R _L = 1.0 Ω I _D ≈ 10 A, V _{GEN} = 4.5 V, R _g = 1 Ω		1.0	1.5	Ω
Rise Time	t _r			35	55	ns
Turn-Off Delay Time	t _{d(off)}			115	175	
Fall Time	t _f			105	160	
Turn-on Delay Time	t _{d(on)}			30	45	
Rise Time	t _r			15	25	
Turn-Off Delay Time	t _{d(off)}			35	55	
Fall Time	t _f			55	85	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			50	A
Pulse Diode Forward Current ^a	I _{SM}				80	
Body Diode Voltage	V _{SD}	I _S = 10 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	I _F = 10 A, di/dt = 100 A/μs, T _J = 25 °C		101	150	ns
Body Diode Reverse Recovery Charge	Q _{rr}			100	150	
Reverse Recovery Fall Time	t _a			75		ns
Reverse Recovery Rise Time	t _b			25		

Notes:

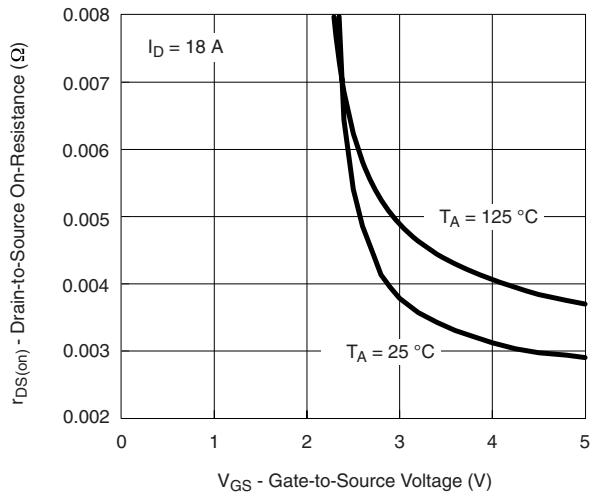
- a. Pulse test; pulse width ≤ 300 μs, duty cycle ≤ 2 %
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

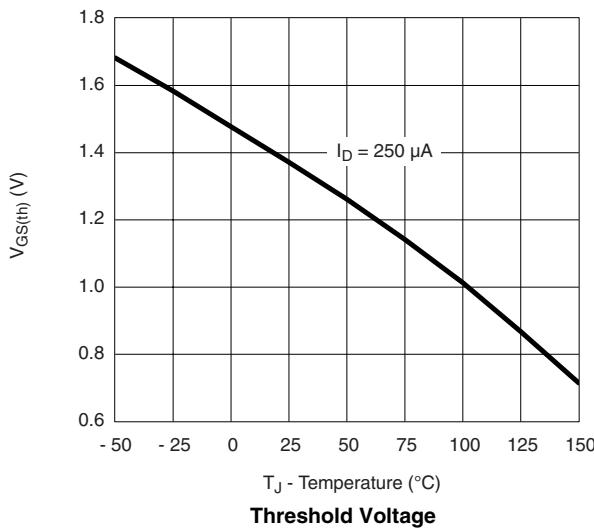
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


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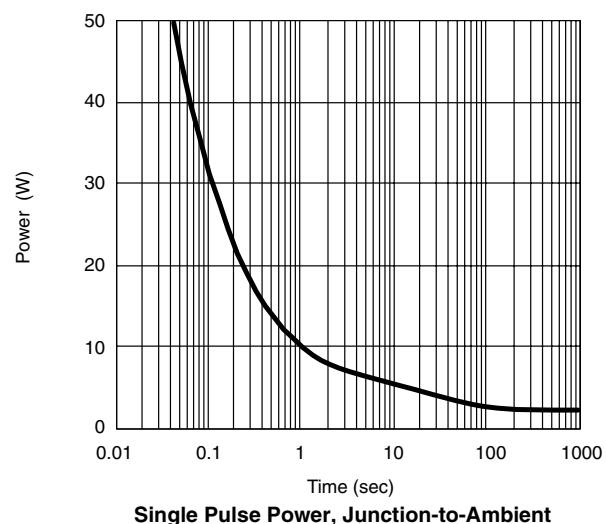
Source-Drain Diode Forward Voltage



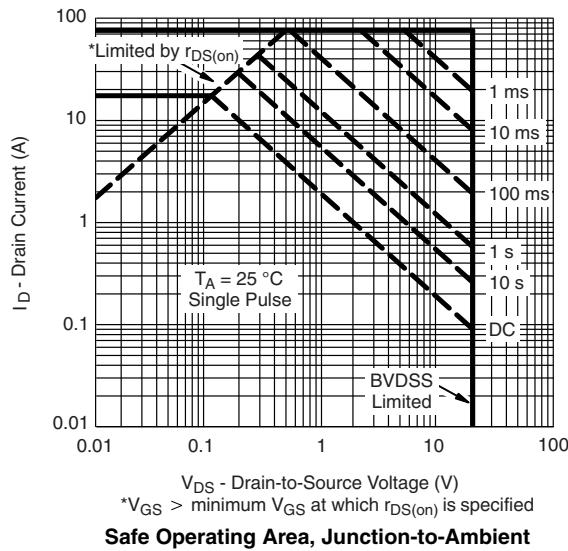
On-Resistance vs. Gate-to-Source Voltage



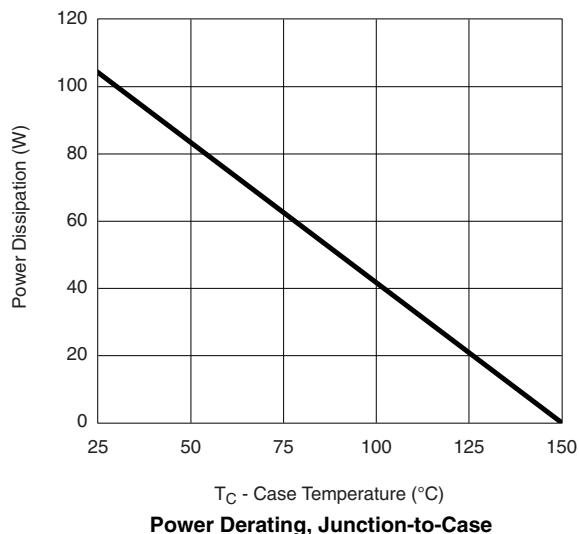
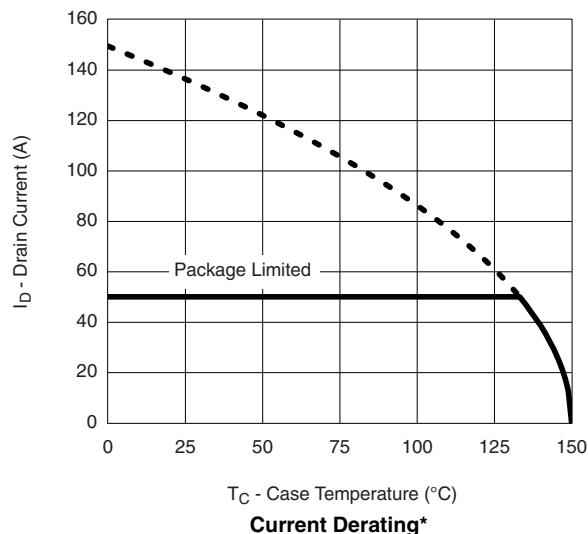
Threshold Voltage



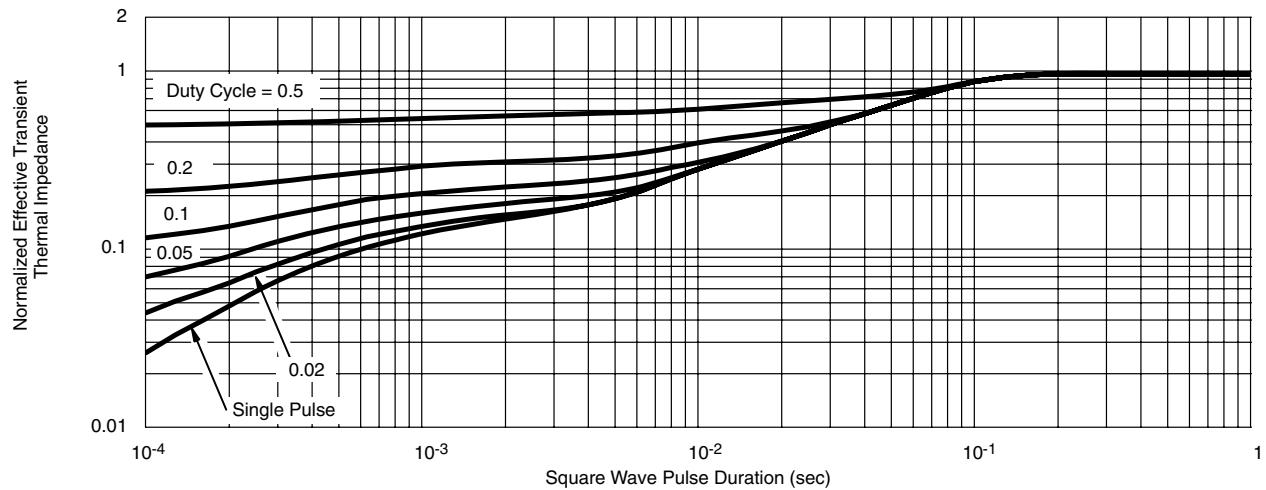
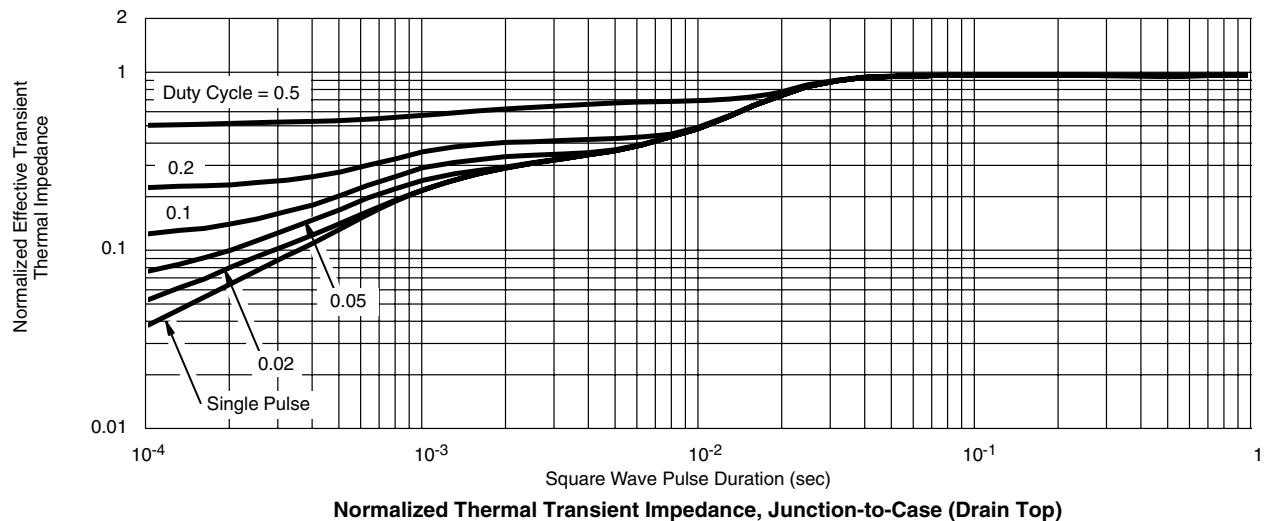
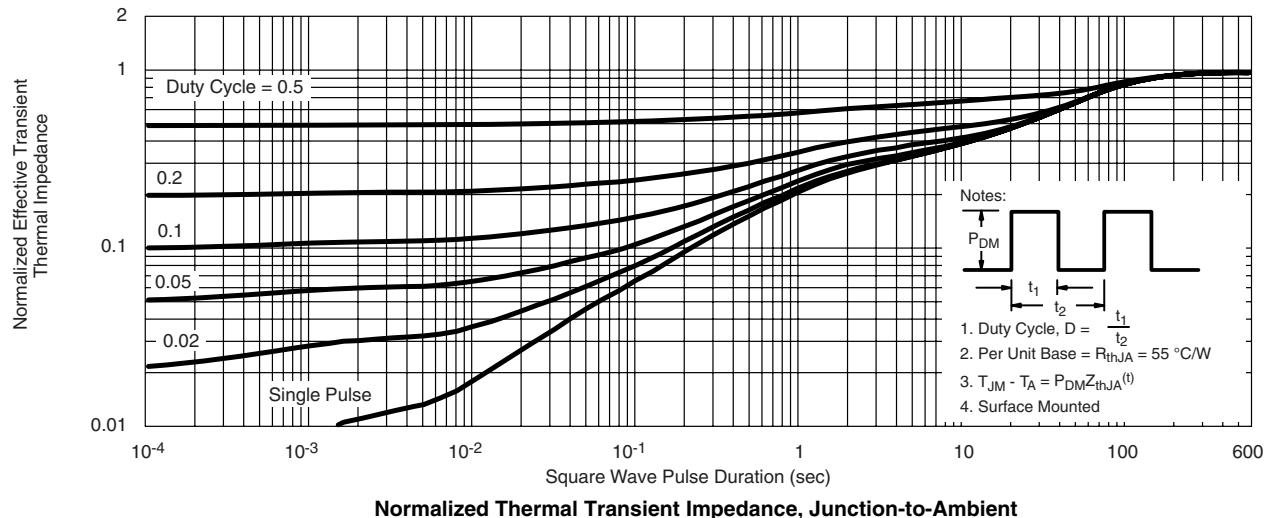
Single Pulse Power, Junction-to-Ambient



Safe Operating Area, Junction-to-Ambient

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


* The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

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